

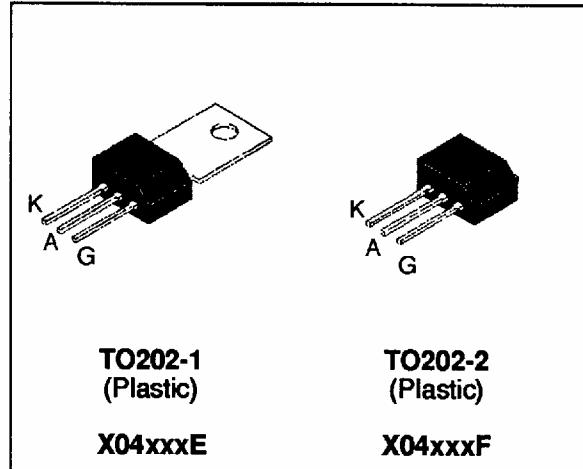
## SENSITIVE GATE SCR

### FEATURES

- $I_{T(RMS)} = 4A$
- $V_{DRM} = 200V$  to  $800V$
- Low  $I_{GT} < 200\mu A$

### DESCRIPTION

The X04xxxE/F series of SCRs uses a high performance TOP GLASS PNPN technology. These parts are intended for general purpose applications where low gate sensitivity is required.



### ABSOLUTE RATINGS (limiting values)

Symbol	Parameter		Value		Unit
$I_{T(RMS)}$	RMS on-state current (180° conduction angle)	X04xxxE/F	$T_c = 90^\circ C$	4	A
		X04xxxF	$T_a = 25^\circ C$	1.35	
$I_{T(AV)}$	Mean on-state current (180° conduction angle)	X04xxxE/F	$T_c = 90^\circ C$	2.5	A
		X04xxxF	$T_a = 25^\circ C$	0.9	
$I_{TSM}$	Non repetitive surge peak on-state current ( $T_j$ initial = $25^\circ C$ )	$t_p = 8.3 \text{ ms}$	33		A
		$t_p = 10 \text{ ms}$	30		
$I^2t$	$I^2t$ Value for fusing	$t_p = 10 \text{ ms}$	4.5		$A^2s$
$dI/dt$	Critical rate of rise of on-state current $I_G = 10 \text{ mA}$ $dI/dt = 0.1 \text{ A}/\mu s$ .	50		$A/\mu s$	
$T_{stg}$ $T_j$	Storage and operating junction temperature range	$-40, +150$ $-40, +125$		$^\circ C$	
$T_I$	Maximum lead temperature for soldering during 10s at 4.5mm from case	260		$^\circ C$	

Symbol	Parameter	Voltage				Unit
		B	D	M	N	
$V_{DRM}$ $V_{RRM}$	Repetitive peak off-state voltage $T_j = 125^\circ C$ $R_{GK} = 1K\Omega$	200	400	600	800	V

X04xxxE/F

### THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R <sub>th(j-a)</sub>	Junction to ambient	X04xxxE	80
		X04xxxF	100
R <sub>th(j-c)</sub>	Junction to case for DC	7.5	°C/W

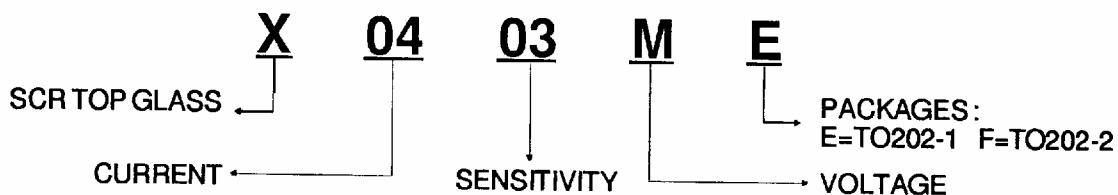
### GATE CHARACTERISTICS (maximum values)

P<sub>G(AV)</sub> = 0.2 W P<sub>GM</sub> = 3 W (tp = 20 μs) I<sub>GM</sub> = 1.2 A (tp = 20 μs)

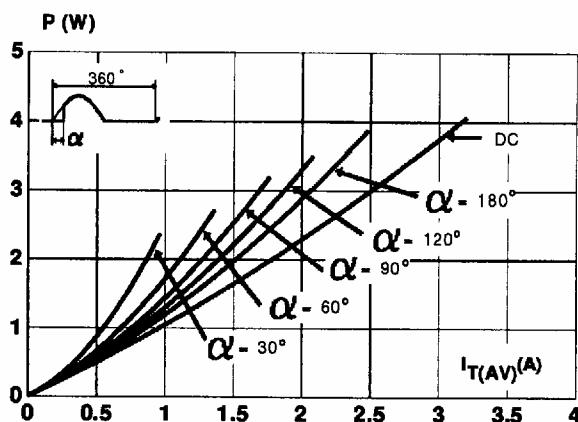
### ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions	Sensitivity			Unit
		02	03	05	
I <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MIN	20	20
			MAX	200	200
V <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MAX	0.8	V
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> R <sub>L</sub> =3.3kΩ R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MIN	0.1	V
V <sub>RGM</sub>	I <sub>RG</sub> =10μA	T <sub>j</sub> = 25°C	MIN	8	V
t <sub>gd</sub>	V <sub>D</sub> =V <sub>DRM</sub> I <sub>TM</sub> = 3 x I <sub>T(AV)</sub> dI <sub>G</sub> /dt = 0.1A/μs I <sub>G</sub> = 10mA	T <sub>j</sub> = 25°C	MAX	2	μs
I <sub>H</sub>	I <sub>T</sub> = 50mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX	5	mA
I <sub>L</sub>	I <sub>G</sub> =1mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX	6	mA
V <sub>TM</sub>	I <sub>TM</sub> = 8A tp= 380μs	T <sub>j</sub> = 25°C	MAX	1.8	V
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>D</sub> = V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ V <sub>R</sub> = V <sub>RRM</sub>	T <sub>j</sub> = 25°C	MAX	5	μA
		T <sub>j</sub> = 110°C	MAX	200	
dV/dt	V <sub>D</sub> =67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 110°C	MIN		10
			TYP	15	20
t <sub>q</sub>	I <sub>TM</sub> = 3 x I <sub>T(AV)</sub> V <sub>R</sub> =35V dI/dt=10A/μs tp=100μs dV/dt=2V/μs V <sub>D</sub> = 67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 110°C	MAX	50	μs

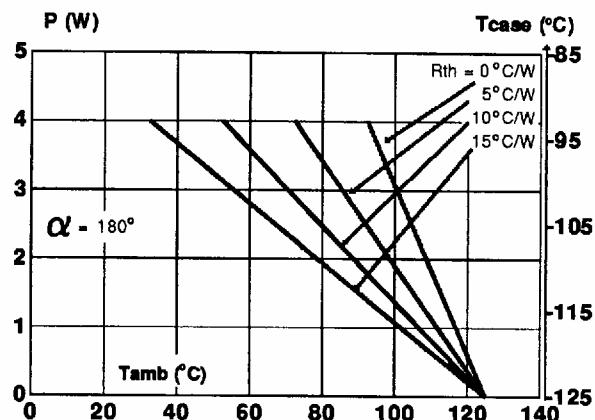
### ORDERING INFORMATION



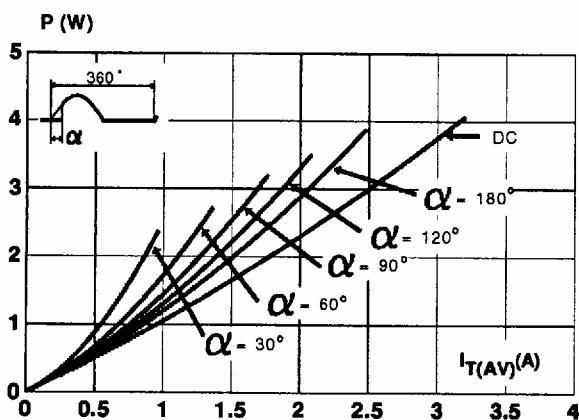
**Fig.1 :** Maximum average power dissipation versus average on-state current (TO202-1).



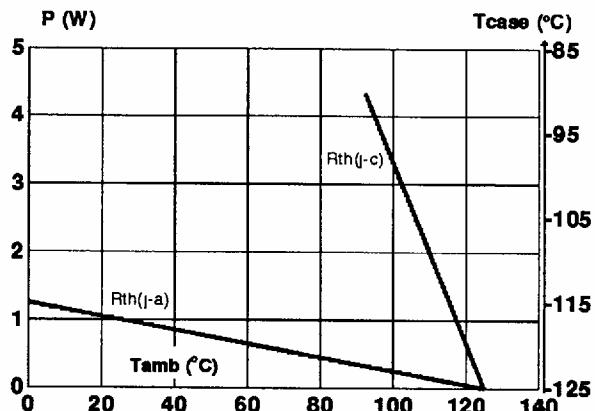
**Fig.2 :** Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Tcase) for different thermal resistances heatsink + contact (TO202-1).



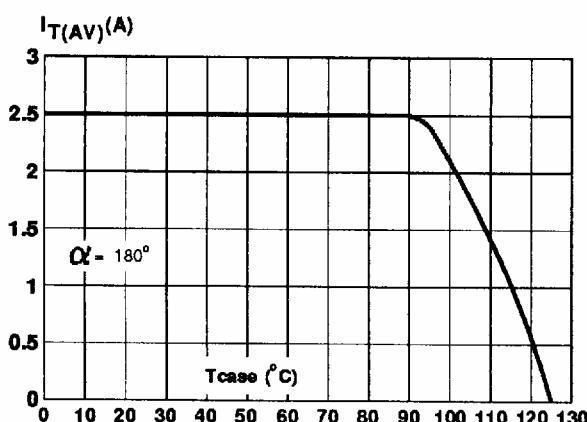
**Fig.3 :** Maximum average power dissipation versus average on-state current (TO202-2).



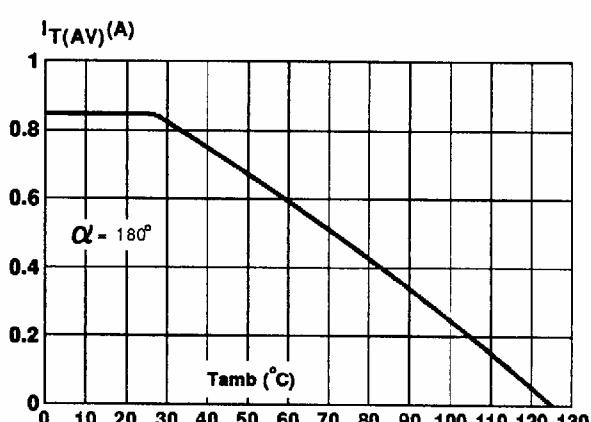
**Fig.4 :** Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Tcase) (TO202-2).



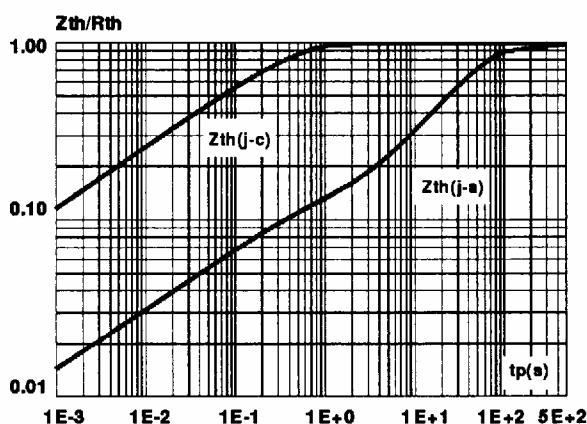
**Fig.5 :** Average on-state current versus case temperature (TO202-1).



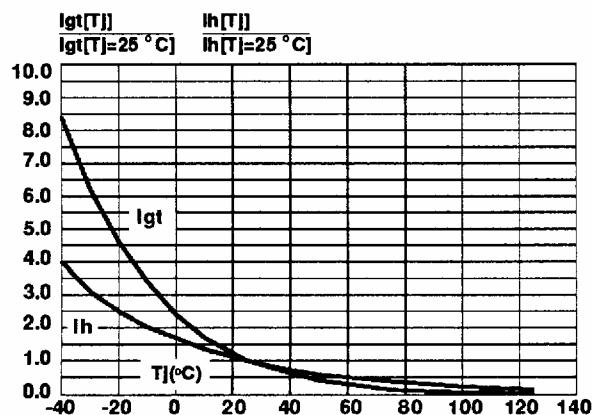
**Fig.6 :** Average on-state current versus case temperature (TO202-2).



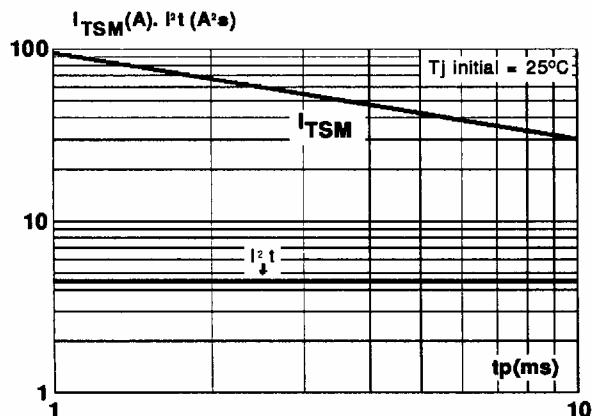
**Fig.7 : Relative variation of thermal impedance versus pulse duration (TO202-1).**



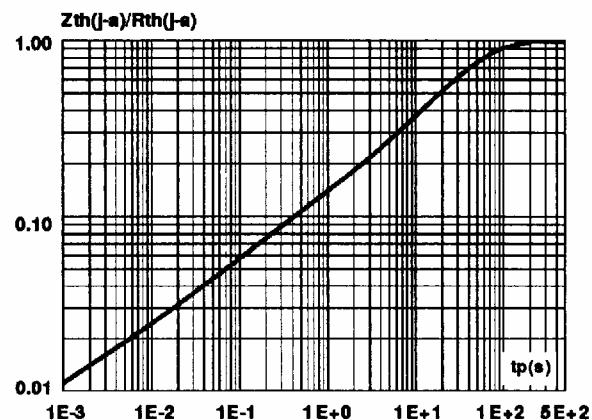
**Fig.9 : Relative variation of gate trigger current and holding current versus junction temperature.**



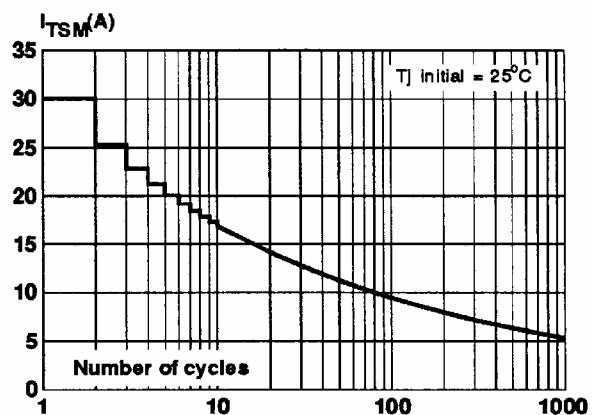
**Fig.11 : Non repetitive surge peak on-state current for a sinusoidal pulse with width : tp ≤ 10ms, and corresponding value of I<sup>2</sup>t.**



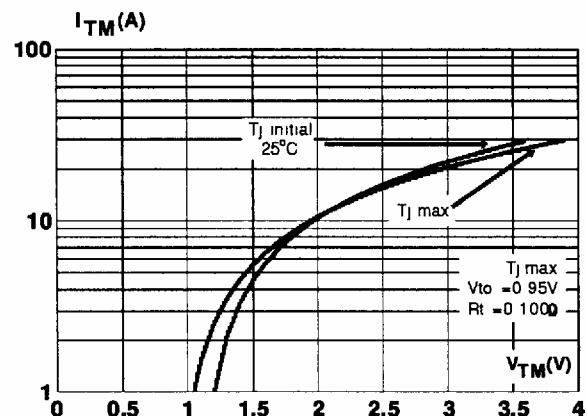
**Fig.8 : Relative variation of thermal impedance junction to ambient versus pulse duration (TO202-2).**



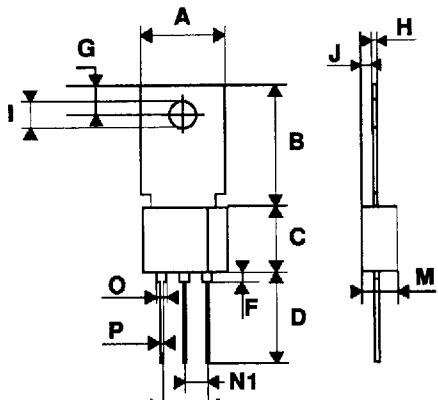
**Fig.10 : Non repetitive surge peak on-state current versus number of cycles.**



**Fig.12 : On-state characteristics (maximum values).**



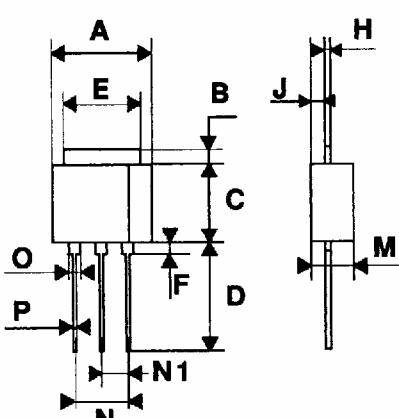
**PACKAGE MECHANICAL DATA**  
TO202-1 (Plastic)



REF.	DIMENSIONS					
	Millimeters			Inches		
	Typ.	Min.	Max.	Typ.	Min.	Max.
A			10.1			0.398
B	13.7			0.540		
C	7.3			0.287		
D	10.5			0.413		
F			1.5			0.059
G	3.2			0.126		
H	0.51			0.020		
I		3.16	3.20		0.124	0.126
J	1.5			0.059		
M	4.5			0.177		
N			5.3			0.209
N1	2.54			0.100		
O			1.4			0.055
P			0.7			0.028

Marking : type number

Weight : 1.4 g

**PACKAGE MECHANICAL DATA**  
TO202-2 (Plastic)


REF.	DIMENSIONS					
	Millimeters			Inches		
	Typ.	Min.	Max.	Typ.	Min.	Max.
A			10.1			0.398
B	1.2			0.047		
C	7.3			0.287		
D	10.5			0.413		
E	7.4			0.290		
F			1.5			0.059
H	0.51			0.020		
J	1.5			0.059		
M	4.5			0.177		
N			5.3			0.209
N1	2.54			0.100		
O			1.4			0.055
P			0.7			0.028

Marking : type number

Weight : 1.0 g

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